

ROHS COMPLIANT HALOGEN

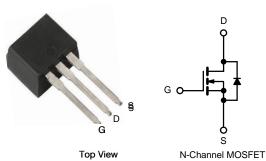
FREE

IRFSL3607-VB Datasheet

N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R_{DS(on)} (Ω) Max.	I _D (A)	Q _g (Typ.)		
80	0.0065 at VGs= 10 V	85 ^a			
	0.0070 at Vgs =6.0 V	80 ^a	17.1 nC		
	0.010 at Vgs =4.5 V	60 ^a			

TO-262



FEATURES

- Trench Power MOSFET
- 100 % $\rm R_g$ and UIS Tested

APPLICATIONS

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting

Parameter		Symbol	Limit	Uni
Drain-Source Voltage	V _{DS}	80	v	
Gate-Source Voltage	V _{GS}	± 20		
	T _C = 25 °C		85 ^a	A
	T _C = 70 °C		65	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	28.6 ^{b, c}	
	T _A = 70 °C		24.9 ^{b, c}	
Pulsed Drain Current (t = 100 µs)		I _{DM}	250	
Constinuous Courses Durin Diada Cumant	T _C = 25 °C	1	85	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	4.5 ^{b, c}	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	30	
L = Single Pulse Avalanche Energy		E _{AS}	45	mJ
	T _C = 25 °C		62.5	w
Maximum Power Dissipation	T _C = 70 °C		40	
	T _A = 25 °C	P _D	5 ^{b, c}	
	T _A = 70 °C		3.2 ^{b, c}	
Operating Junction and Storage Temperature F	T _J , T _{stg}	- 55 to 150	**	
Soldering Recommendations (Peak Temperatur		260		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	20	25	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.5	2.0	0/10		

Notes

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.

f. Maximum under steady state conditions is 70 °C/W.

d. The TO-220 is a leadless package. The end of the lead terminal is exposed

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	80			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	/Τ_		37			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μΑ		- 6.1		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th})	V _{DS} = V _{GS} , I _D = 250 μA	2.0		4.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
	I _{DSS}	$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current		V _{DS} = 80 V, V _{GS} = 0 V, T _J = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 V, V_{GS} = 10 V$	30			А	
		V _{GS} = 10 V, I _D = 20 A		0.0065		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 6 V, I _D = 15 A		0.0070			
	- (-)	V _{GS} = 4.5 V, I _D = 10 A		0.0100			
Forward Transconductance ^a	g _{fs}	V _{DS} = 10 V, I _D = 20 A		60		S	
Dynamic ^b							
Input Capacitance	C _{iss}			8000			
Output Capacitance	C _{oss}	V _{DS} = 40 V, V _{GS} = 0 V, f = 1 MHz		950		pF	
Reverse Transfer Capacitance	C _{rss}			276			
Total Gate Charge	Qg	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		35.5	54		
		$V_{DS} = 40 \text{ V}, V_{GS} = 6 \text{ V}, I_{D} = 10 \text{ A}$		22	33	3	
				17.1	26	nC	
Gate-Source Charge	Q _{gs}	V _{DS} = 40 V,V _{GS} = 4.5 V, I _D = 10 A		5.3			
Gate-Drain Charge	Q _{gd}			7.3			
Output Charge	Q _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86		
Gate Resistance	Rg	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	$V_{DD} = 40 \text{ V}, \text{ R}_{\text{I}} = 4 \Omega$		8	16	-	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{\text{GEN}} = 10 \text{ V}, \text{ R}_g = 1 \Omega$		32	64		
Fall Time	t _f			7	14		
Turn-On Delay Time	t _{d(on)}			14	28	ns	
Rise Time	t _r	$V_{DD} = 40 \text{ V}, \text{ R}_{\text{I}} = 4 \Omega$		11 22			
Turn-Off DelayTime	t _{d(off)}			30	60	-	
Fall Time	t _f			8	16	1	
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			75		
Pulse Diode Forward Current (t = 100 µs)	I _{SM}	-		1	150	A	
Body Diode Voltage	V _{SD}	I _S = 5 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}	-		38	75	ns	
		-		36	70	nC	
Reverse Recovery Fall Time	Q _{rr} t _a	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_\text{J} = 25 \ ^\circ\text{C}$		19			
Reverse Recovery Rise Time	t _b			19		ns	

Notes

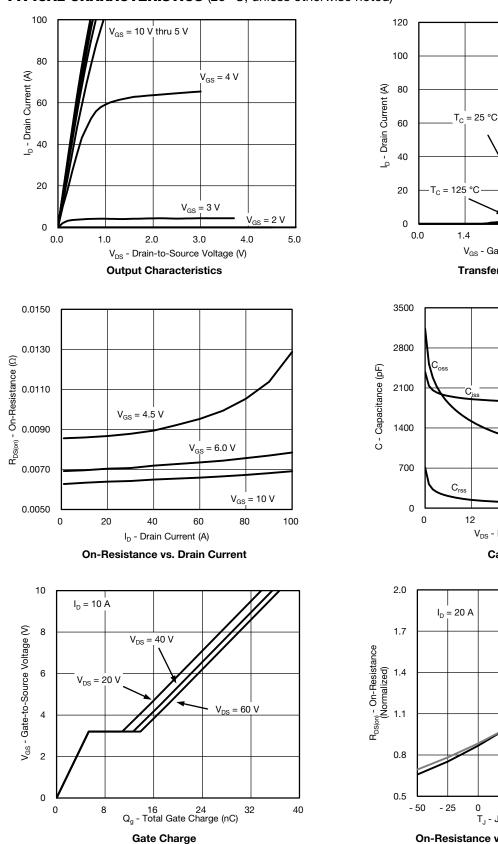
a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$

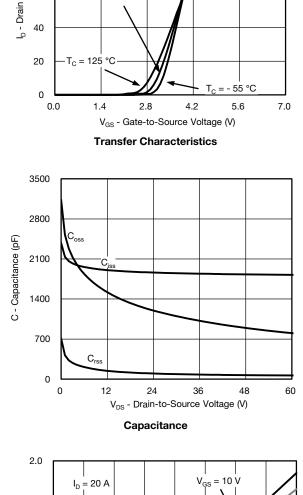
b. Guaranteed by design, not subject to production testing.

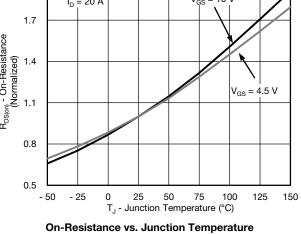
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Bsemi

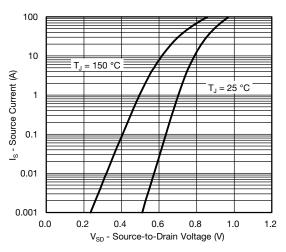


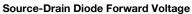


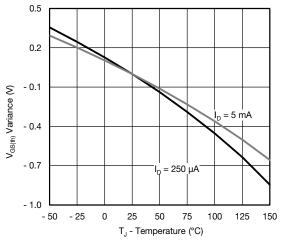




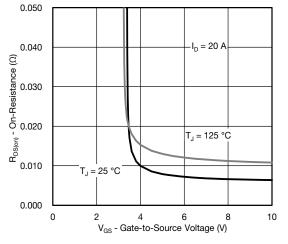




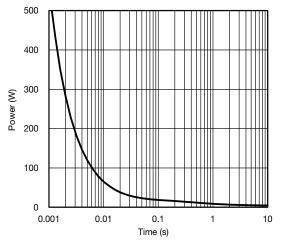




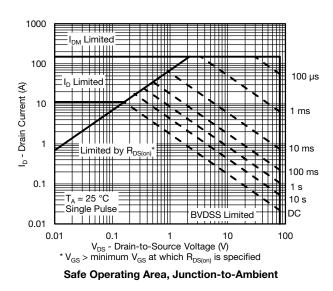




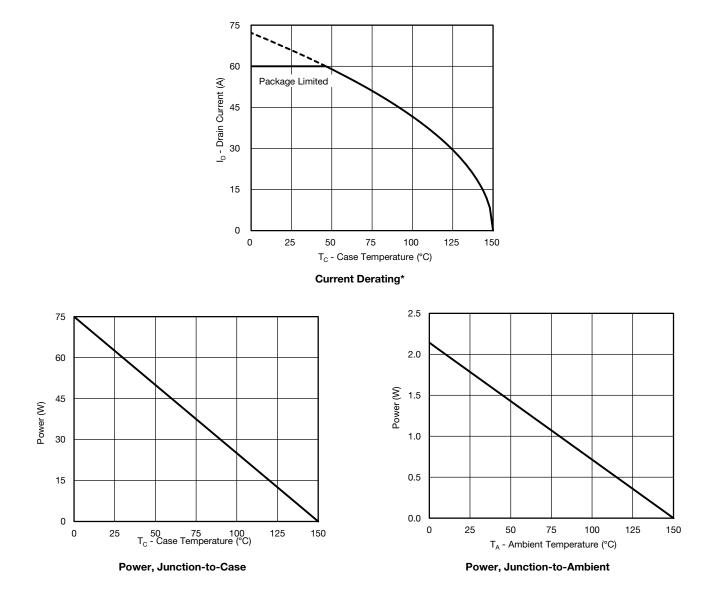
On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

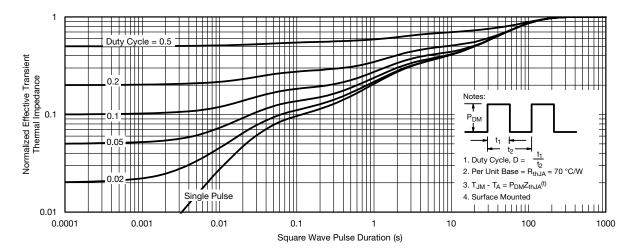




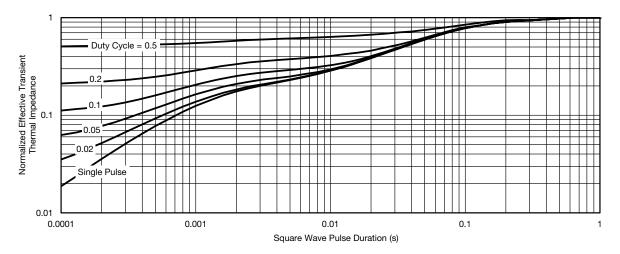


* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





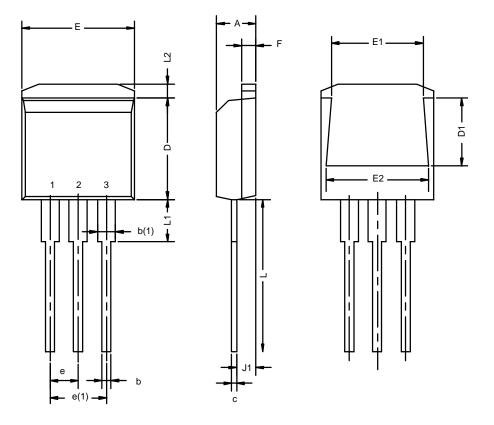




Normalized Thermal Transient Impedance, Junction-to-Case



TO-262: 3-LEAD



	MILLIM	ETERS*	INC	NCHES		
Dim	Min	Max	Min	Max		
Α	4.32	4.70	0.170	0.185		
b	0.64	1.00	0.025	0.039		
b(1)	1.14	1.40	0.045	0.055		
С	0.36	0.50	0.014	0.020		
D	8.64	9.65	0.340	0.380		
D1	5.59	6.10	0.220	0.240		
е	2.41	2.67	0.095	0.105		
e(1)	4.95	5.33	0.195	0.210		
E	10.03	10.41	0.395	0.410		
E1	7.87	8.64	0.310	0.340		
E2	9.02	9.53	0.355	0.375		
F	1.14	1.40	0.045	0.055		
J1	2.41	2.79	0.095	0.110		
L	13.08	14.22	0.515	0.560		
L1	-	3.81	-	0.150		
L2	1.02	1.40	0.040	0.055		
ECN: T-02234—Rev. C, 14-Oct-02 DWG: 5855						

 $\ensuremath{^*\text{Use}}$ millimeters as the primary measurement



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